Applicant(s)/Patent Under Reexamination Application/Control No. 10/042,142 LIN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Alicia Baturay 2155 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,732,315 B2 05-2004 Α Yagil et al. 714/755 US-В US-С US-D US-Ε US-F

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